



The State of NEPP NASA Electronic Parts & Packaging Program

Peter Majewicz, Manager NEPP Program peter.majewicz@nasa.gov

NASA/GSFC

Jonny Pellish, Dep Manager, NEPP Program jonathan.pellish@nasa.gov

NASA/GSFC

Shri Agarwal, Coordinator, NEPAG, shri.g.agarwal@jpl.nasa.gov NASA/JPL

http://nepp.nasa.gov

To be presented by P. Majewicz at the NEPP Electronics Technology Workshop (ETW), Greenbelt, MD, June 15-18, 2020.





Acronyms

| Abbreviation | Definition | Abbreviation | Definition |
|--------------|--|--------------|--|
| AF | Air Force | NASA | National Aeronautics and Space Administration |
| BGA | Ball Grid Array | NEPAG | NASA Electronic Parts Assurance Group |
| BN | Bayesian Network | NEPP | NASA Electronic Parts and Packaging (Program) |
| ВоК | Body of Knowledge | NESC | NASA Engineering and Safety Center |
| CMOS | Complementary Metal Oxide Semiconductor | NODIS | NASA Online Directives Information System |
| COTS | Commercial Off the Shelf | NPR | NASA Procedural Requirement |
| CPU | Central Processing Unit | NRO | National Reconnaissance Office |
| DDR | Double Data Rate | NSREC | Nuclear and Space Radiation Effects Conference |
| DLA | Defense Logistics Agency | OCE | Office of the Chief Engineer |
| DMEA | Defense Microelectronics Activity | OGA | Other Government Agency |
| DoD | Department of Defense | PIC | Photonic Integrated Circuit |
| DoE | Department of Energy | POC | Point of Contact |
| EEE | Electrical, Electronic, and Electromechanical | PoF | Physics of Failure |
| ETW | Electronics Technology Workshop | RF | Radio Frequency |
| FPGA | Field Programmable Gate Array | RH | Radiation Hardened |
| GaN | Gallium Nitride | RHA | Radiation Hardness Assurance |
| GIDEP | Government Industry Data Exchange Program | SAPP | Space Asset Protection Program |
| GPU | Graphics Processing Unit | SDRAM | Synchronous Dynamic Random Access Memory |
| GRC | Glenn Research Center | SEE | Single-Event Effects |
| GSFC | Goddard Space Flight Center | SiC | Silicon Carbide |
| GSN | Goal Structuring Notation | SMA | Safety and Mission Assurance |
| HQ | Headquarters | SMC | Space and Missile Systems Center |
| IC | Integrated Circuit | SOA | Safe Operating Area |
| IEEE | Institute of Electrical and Electronics Engineers | SoC | System on a Chip |
| JPL | Jet Propulsion Laboratory | SRAM | Static Random Access Memory |
| JSC | Johnson Space Center | SSAI | Science Systems and Applications, Inc. |
| LaRC | Langley Research Center | STMD | Space Technology Mission Directorate |
| LGA | Land Grid Array | STT | Spin Transfer Torque |
| MAPLD | Military and Aerospace Programmable Logic Devices (Workshop) | SysML | System Modeling Language |
| МВМА | Model-Based Mission Assurance | TID | Total Ionizing Dose |
| MRAM | Magnetic Random Access Memory | TSV | Thru-Silicon Via |
| MSFC | Marshall Space Flight Center | | |



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NEPP Overview – Mission Statement

Provide NASA's leadership for developing and maintaining guidance for the screening, qualification, test, and reliable use of EEE parts by NASA, in collaboration with other government agencies and industry.







NEPP Overview – Mission Statement

Provide NASA's leadership for developing and maintaining guidance for the screening, qualification, test, and reliable use of EEE parts by NASA, in collaboration with other government agencies and industry.







Standards, Policy Documents, Guidance, Procedures and Reports

- Updating EEE-INST-002, Instructions for EEE Parts Selection, Screening, Qualification, and Derating
 - Transforming to an Agency level document
- Updating NPR-8705.4, Risk Classification for NASA Payloads
 - Appendix D Recommended SMA-Related Program Requirements for NASA Class A-D Payloads
 - Contains a mapping for EEE Parts that recommends parts with respect to payload class (A-D) and to part grade level (space, military, industrial, COTS, etc.)
- Body of Knowledge (BoK) documents
 - Copper Wire Bonds (Sampson/Rutkowski, 2018)
 - Graphics Processor Units (Wywras, 2018)
 - Cracking Problems in Low-Voltage Chip Ceramic Capacitors (Teverovsky, 2018)
- Evaluation Reports
 - Commercial LIDARS (Ott, 2020)
 - Isolated Gate Driver at Extreme Temperature (Boomer, 2020)
- Numerous papers and presentations
 - Approximately 100 deliverables a year
 - Posted to NEPP website



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Provide NASA's leadership for developing and maintaining guidance for the screening, qualification, test, and reliable use of EEE parts by NASA, in collaboration with other government agencies and industry.

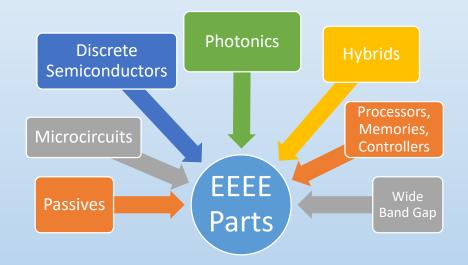






EEEE (Quad-E) Parts

• Electrical, Electronic, Electro-Mechanical & Electro-Optic (EEEE) Parts

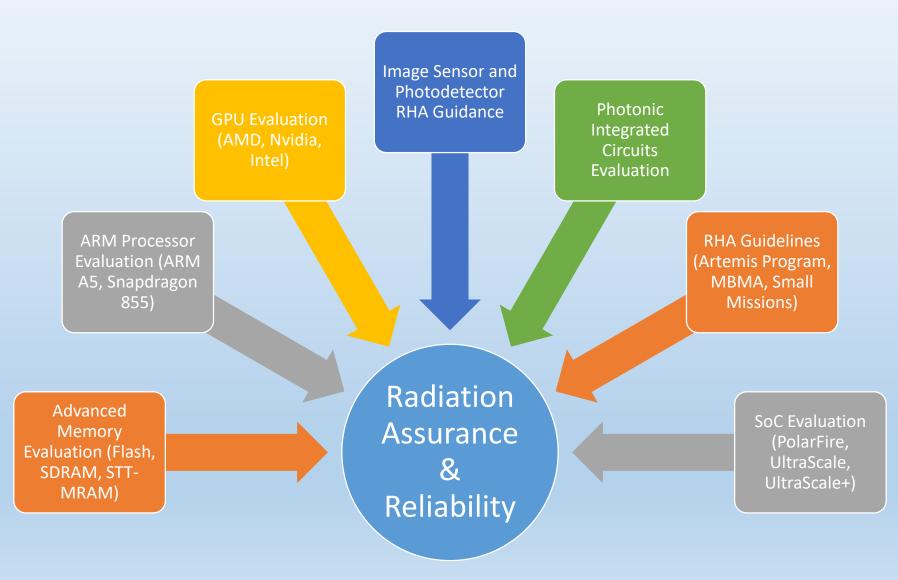


COTS ------Automotive------Industrial----- " New Space"-----MILSPEC



Radiation Work







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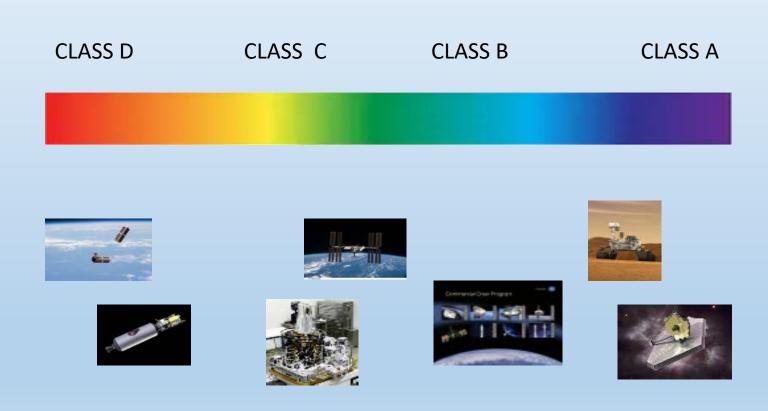
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NPR-8705.4, Risk Classification for NASA Payloads







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KEY FOCUS POINTS



TELECONFERENCES NEPAG

- Weekly Domestic
- Monthly International

Government Working Group

- Biweekly

Other specialty areas

- Hybrids
- 2.5 & 3D Packaging
- Small Mission Success

SUPPORT DEFENSE STANDARDIZATION PROGRAM / DEFENSE LOGISTICS AGENCY (DLA)

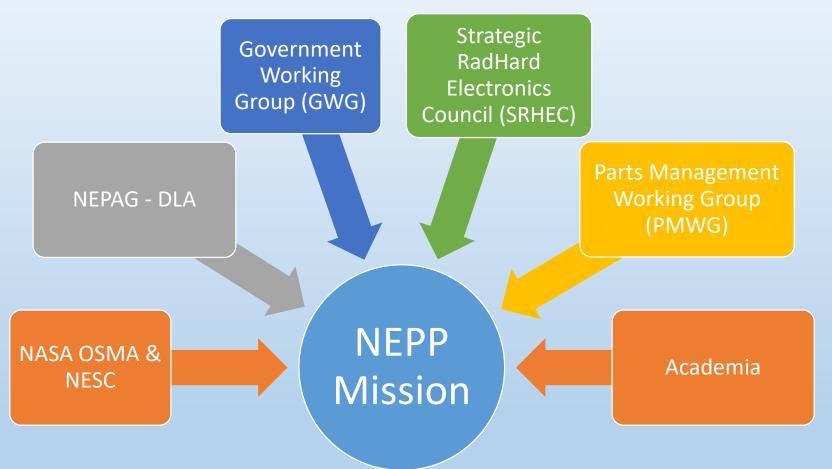
- DLA audits
- Review MILSPEC Changes
- Attend JEDEC and SAE WG meetings
 - Class Y, PEMS, PEDS incorporation into MIL SPECS

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NEPP Collaborations



Air Force – SMC/The Aerospace Corporation; Air Force – Wright-Patterson; Army; MDA; NASA Centers; Navy – NSWC Crane Division; NRO/The Aerospace Corporation





Conclusion: NEPP Program



¹⁴ To be presented by P. Majewicz at the NEPP Electronics Technology Workshop (ETW), Greenbelt, MD, June 15-18, 2020.





Questions?